

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

10/631,082

Confirmation No. 2031

Applicant Filed

Hechtl et al. 07/31/2003

TC/A.U.

TBD

Examiner

TBD

Docket No.

TID-34165

Customer No.

23494

Title

METHOD OF INSPECTING A MASK

ART CITE

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

MAILING CERTIFICATE

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P. O. Box 1450, Alexandria, VA 22313-1450.

Marianna Smith

11-20-02 Date

Dear Sir:

Please make the references listed on the enclosed PTO-1449 of record under 37 C.F.R. 1.56, 1.97, and 1.98 in the patent application identified above. They were cited in a corresponding German patent application. Copies of the listed references are enclosed.

Respectfully submitted,

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o, no persons are rec	uired to respond to a collection of inform	nation unless it displays a valid OMB control number.			
	Complete If Known				
	Application Number	10/631,082			
	Filing Date	07/31/2003			
	First Named Inventor	Christoph Hechtl			
	Group Art Unit	TBD			
	Examiner Name	TBD			
1	Attorney Docket No.	TID-34165			
	o, no persons are req	Application Number Filing Date First Named Inventor Group Art Unit Examiner Name			

				U.S	S. PATENT DOCU	MENTS
Exam. Initials		U.S. Patent Do	cument	Name of Patentee	Date of Pub.	
	Cite No.1	Number	Kind Code ² (if known)	or Applicant of Cited Doc.	of Cited Doc. (mm-yyyy)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	AA	4,906,326		Amemiya et al.	3/9/1990	
	AB	2002/0024019A1		Matsuoka	2/28/2002	
	AC					
	AD					
	AE					
	AF					
	AG			·		
	АН					

	,	,			FOREIGN PATE	NT DOCUMENTS		
Exam. Initials*	Cite No.1	Foreign Patent Document			Name of Patentee	Date of Pub.		T
		Office ³	Number⁴	Kind Code ² (if known)	or Applicant of Cited Doc.	of Cited Doc. (mm-dd-yyyy)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T⁰
	BA	DE	689 23 638 T2		Amemiya	01/18/1996		
	BB	DE	101 41 422 A1		Matsuoka	05/08/2002		
	ВС	EP	0 334 680 B1		Amemiya	08/02/1995	Abstract	
	BD							
	BE							
	BF							
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		OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	
Exam. Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
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US and Foreign Patent Documents: ¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 4For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the senal number of the patent document. Skind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. Applicant is to place a check mark here if English language Translation is attached.

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